

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No. 10/539,247 Conf. No. 9258
In Re Application of: Gattiker *et al.* Art Unit: 2829
Filed: 06/16/2005 Dkt. #: BUR920020068US1 (IBMF-0010)
Examiner: Nguyen, Vinh P.

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS
MODIFICATION**

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REPALCEMENT AMENDMENT

Sir:

I. INTRODUCTORY COMMENTS

In response to the Office Action of June 11, 2007, and further in response to the Notice of Non-Compliant Amendment of November 14, 2007, please reconsider the above-referenced patent application in light of the following remarks:

The Claims are reflected in the listing of claims that begin on page 2 of this paper.

Remarks begin on page 9 of this paper.